Notice of References Cited Application/Control No. Applicant(s)/Patent Under Reexamination LEE, SANG SUN Examiner Art Unit Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,101,180	08-2000	Donahue et al.	370/352
	В	US-6,181,326	01-2001	Takahashi, Naomasa	345/158
	С	US-5,734,853	03-1998	Hendricks et al.	715/716
	D.	US-5,861,906	01-1999	Dunn et al.	725/87
	E	US-5,805,763	09-1998	Lawler et al.	386/83
	F	US-6,314,572	11-2001	LaRocca et al.	725/60
	G	US-6,904,610	06-2005	Bayrakeri et al.	725/54
	Н	US-6,169,543	01-2001	Wehmeyer, Keith Reynolds	725/47
	1	US-2005/0028208	02-2005	Ellis et al.	725/058
	J	US-			
	к	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	α					
	R					
	S					
	_					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	C	
	٧	
	w	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.